TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 0 9 1

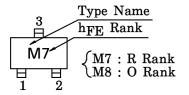
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

- Low Noise Figure, High Gain.
- NF=1.1dB, $|S_{21e}|^2 = 7dB$ (f=1GHz)

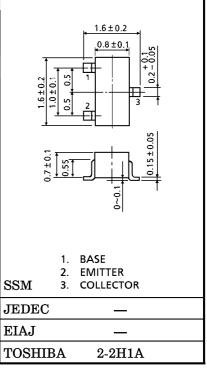
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	V _{CBO}	20	V
Collector-Emitter Voltage	v_{CEO}	10	V
Emitter-Base Voltage	$V_{ m EBO}$	1.5	V
Base Current	$I_{\mathbf{B}}$	20	mA
Collector Current	$I_{\mathbf{C}}$	40	mA
Collector Power Dissipation	$P_{\mathbf{C}}$	100	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	$^{\circ}\mathrm{C}$

MARKING



Unit in mm



Weight: 2.4mg

MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_{T}$	$V_{CE}=8V, I_{C}=20mA$	7	10	_	GHz
Insertion Gain	$ S_{21e} ^2$ (1)	V_{CE} =8V, I_{C} =20mA, f=1GHz	10	13	_	dB
	$ S_{21e} ^2$ (2)	V_{CE} =8V, I_{C} =20mA, f =2GHz	_	7	_	uD
Noise Figure	NF (1)	$V_{CE}=8V$, $I_{C}=5mA$, $f=1GHz$	_	1.1	2.5	dB
	NF (2)	$V_{CE}=8V$, $I_{C}=5mA$, $f=2GHz$	_	1.7	_	uБ

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB}=1V, I_{C}=0$	_	_	1	μ A
DC Current Gain	hFE (Note 1)	$V_{CE}=8V, I_{C}=20mA$	50	_	160	_
Output Capacitance	$C_{\mathbf{ob}}$	$V_{CB} = 10V, I_{E} = 0, f = 1MHz$	1	0.7	_	pF
Reverse Transfer Capacitance	$\mathrm{c_{re}}$	(Note 2)	_	0.5	0.95	pF

(Note 1) hFE Classification $R:50\sim100$, $O:80\sim160$

(Note 2) Cre is measured by 3 terminal method with capacitance bridge.

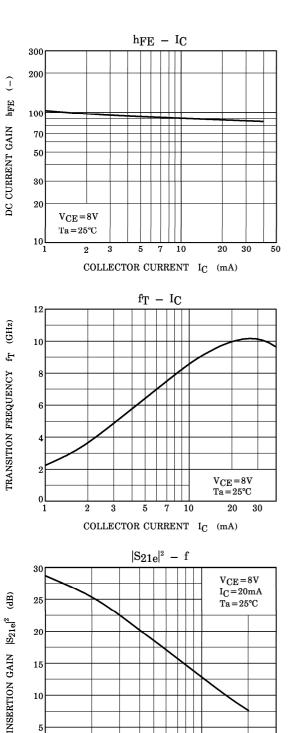
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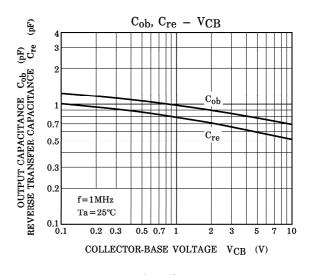
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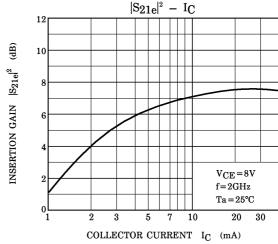
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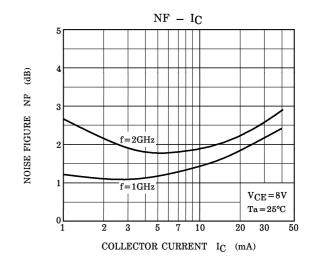
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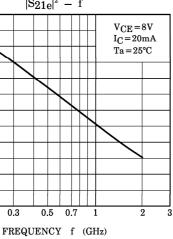
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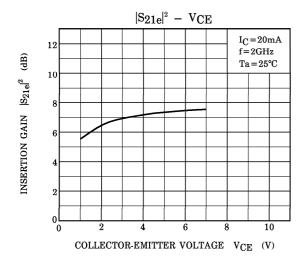


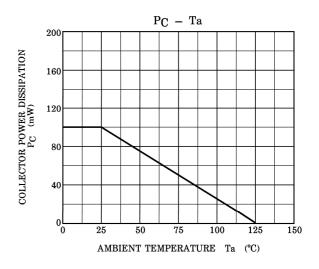






2 2001-05-31





S-Parameter $Z_O = 50\Omega$, $Ta = 25^{\circ}C$ $V_{CE} = 8V$, $I_C = 5mA$

frequency	S11		S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.683	-50.1	10.186	138.3	0.049	62.0	0.773	-30.0
400	0.462	-86.9	7.472	114.6	0.071	54.3	0.556	-39.6
600	0.343	-113.1	5.618	100.9	0.086	53.8	0.448	-41.7
800	0.282	-133.6	4.407	91.7	0.101	55.3	0.392	-41.6
1000	0.249	-151.0	3.663	84.7	0.115	57.2	0.360	-41.7
1200	0.236	-166.6	3.128	78.7	0.131	58.9	0.339	-41.7
1400	0.233	179.7	2.759	73.1	0.150	60.1	0.330	-42.8
1600	0.234	168.3	2.457	68.2	0.168	60.0	0.319	-45.0
1800	0.238	158.6	2.224	63.4	0.185	60.0	0.311	-47.9
2000	0.251	149.6	2.038	59.4	0.203	60.4	0.302	-50.2

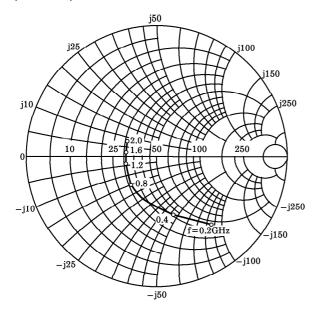
$V_{CE} = 8V$, $I_C = 20mA$

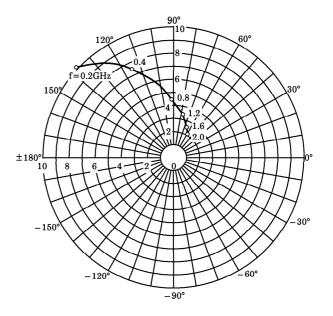
frequency	equency S11		S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.319	-91.9	18.338	116.7	0.033	65.3	0.494	-43.5
400	0.213	-134.2	10.303	99.2	0.054	68.9	0.312	-42.4
600	0.185	-160.0	7.111	90.3	0.076	70.8	0.258	-37.6
800	0.176	-178.2	5.415	84.3	0.098	71.2	0.236	-34.3
1000	0.174	167.8	4.400	79.2	0.120	71.1	0.228	-32.0
1200	0.178	156.8	3.712	74.8	0.143	70.3	0.226	-31.5
1400	0.186	147.5	3.236	70.3	0.168	68.7	0.226	-32.8
1600	0.194	139.7	2.874	66.3	0.190	66.6	0.223	-35.9
1800	0.199	133.7	2.583	62.6	0.211	64.9	0.216	-39.0
2000	0.215	127.8	2.369	58.8	0.232	63.5	0.211	-41.9

3 2001-05-31

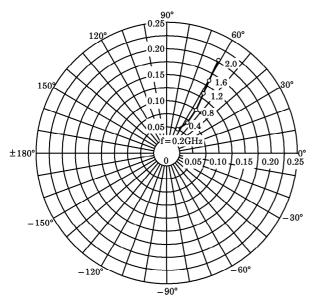
 $\begin{array}{l} S_{11e} \\ V_{CE} = 8V \\ I_{C} = 5mA \\ Ta = 25^{\circ}C \\ (UNIT:\Omega) \end{array}$

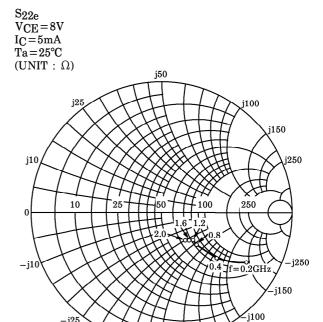










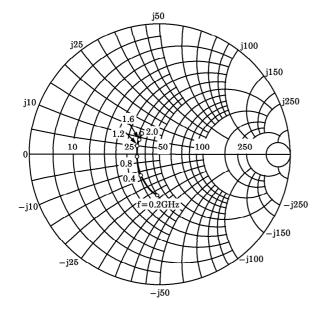


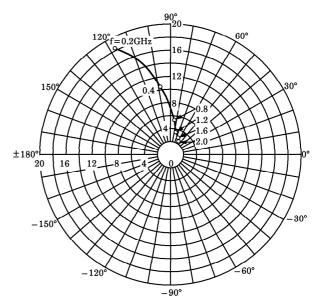
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4 2001-05-31

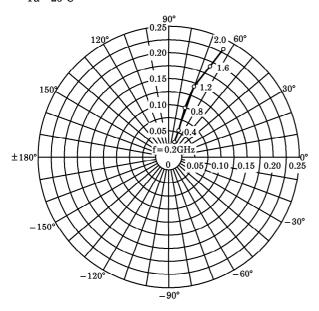
 $\begin{array}{l} S_{11e} \\ V_{CE} = 8V \\ I_{C} = 20 \text{mA} \\ Ta = 25 ^{\circ}\text{C} \\ (UNIT:\Omega) \end{array}$





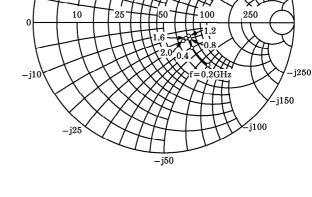


 $\begin{array}{l} S_{12e} \\ V_{CE} = 8V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \end{array}$



 $S_{22e} \\ VCE = 8V \\ IC = 20mA \\ Ta = 25^{\circ}C \\ (UNIT:\Omega)$

j10



j100

j150

j250

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